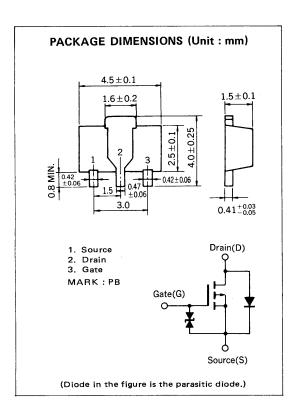


# MOS FIELD EFFECT TRANSISTOR **2SJ197**

# P-CHANNEL MOS FET FOR SWITCHING



The 2SJ197, P-channel vertical type MOS FET, is a switching device which can be driven directly by the output of ICs having a 5 V power source.

As the MOS FET has low on-state resistance and excellent switching characteristics, it is suitable for driving actuators such as motors, relays, and solenoids.

#### **FEATURES**

- Directly driven by ICs having a 5 V power supply.
- Has low on-state resistance  $R_{DS(on)} = 1.5~\Omega~MAX.~@V_{GS} = -4.0~V,~I_D = -0.5~A$   $R_{DS(on)} = 1.0~\Omega~MAX.~@V_{GS} = -10~V,~I_D = -0.5~A$
- Complementary to 2SK1483

#### QUALITY GRADE

Standard

Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

# ABSOLUTE MAXIMUM RATINGS (Ta = 25 °C)

PARAMETER	SYMBOL	RATINGS	UNIT	TEST CONDITIONS
Drain to Source Voltage	V <sub>DSS</sub>	60	V	V <sub>GS</sub> = 0
Gate to Source Voltage	VGSS	∓20	V	V <sub>DS</sub> = 0
Drain Current	I <sub>D(DC)</sub>	∓1.5	Α	
Drain Current	I <sub>D</sub> (pulse)	∓3.0	Α	PW ≤ 10 ms, Duty Cycle ≤ 50 %
Total Power Dissipation	PT	2.0	w	when using ceramic board of 16 cm <sup>2</sup> x 0.7 mm
Channel Temperature	T <sub>ch</sub>	150	°C	
Storage Temperature	T <sub>stg</sub>	-55 to +150	°C	

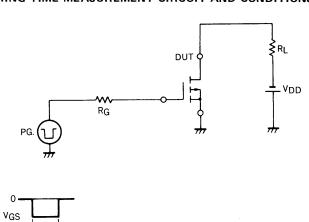
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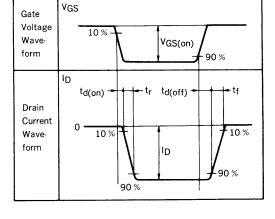


# ELECTRICAL CHARACTERISTICS ( $T_a = 25$ °C)

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITION
Drain Cut-off Current	IDSS			-10	μΑ	V <sub>DS</sub> = -60 V, V <sub>GS</sub> = 0
Gate Leakage Current	IGSS			∓10	μΑ	$V_{GS} = \mp 20 \text{ V}, V_{DS} = 0$
Gate Cut-off Voltage	V <sub>GS(off)</sub>	-1.0	-2.1	-3.0	٧	$V_{DS} = -10 \text{ V, } I_{D} = -1 \text{ mA}$
Forward Transfer Admittance	ly <sub>fs</sub> l	0.4	1.0		s	$V_{DS} = -10 \text{ V}, I_{D} = -0.5 \text{ A}$
Drain to Source On-State Resistance	R <sub>DS(on)1</sub>		0.9	1.5	Ω	V <sub>GS</sub> = -4.0 V, I <sub>D</sub> = -0.5 A
Drain to Source On-State Resistance	R <sub>DS(on)2</sub>		0.5	1.0	Ω	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -0.5 A
Input Capacitance	C <sub>iss</sub>		220		рF	V <sub>DS</sub> = -10 V, V <sub>GS</sub> = 0, f = 1 MHz
Output Capacitance	Coss		125		pF	
Feedback Capacitance	C <sub>rss</sub>		17		рF	
Turn-On Delay Time	<sup>t</sup> d(on)		45		ns	
Rise Time	t <sub>r</sub>		70		ns	$V_{GS(on)} = -10 \text{ V}, R_G = 10 \Omega, V_{DD} = -25 \text{ V},$ $I_D = -0.5 \text{ A}, R_L = 50 \Omega$
Turn-Off Delay Time	<sup>t</sup> d(off)		380		ns	
Fall Time	t <sub>f</sub>		170		ns	

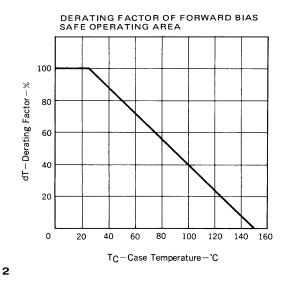
### SWITCHING TIME MEASUREMENT CIRCUIT AND CONDITIONS

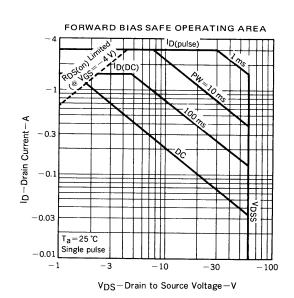


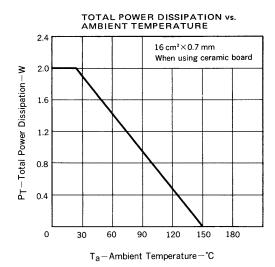


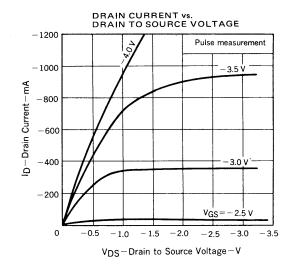
TYPICAL CHARACTERISTICS ( $T_a = 25$  °C)

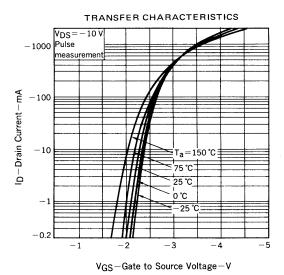
Duty Cycle ≤ 1 %

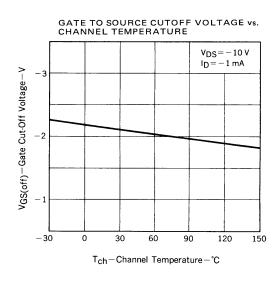


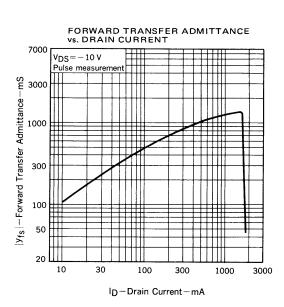


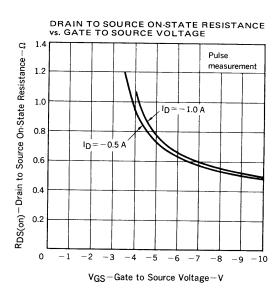


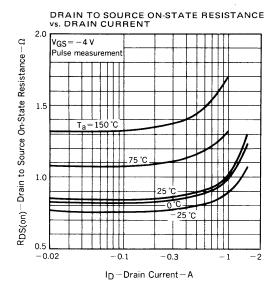


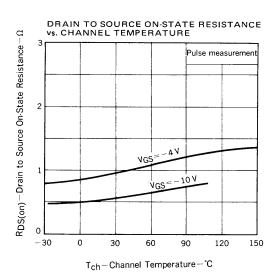


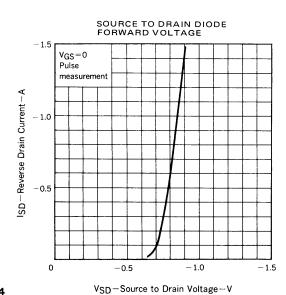


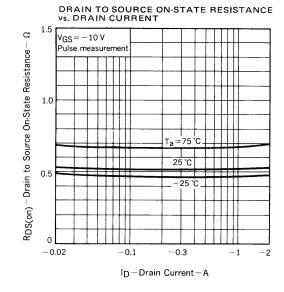


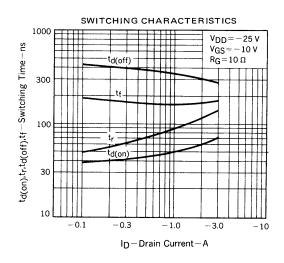














# RECOMMENDED SOLDERING CONDITIONS

Mounting of this product by soldering should be done under the following conditions. Please consult our representatives about soldering methods and conditions other than these.

#### **SURFACE MOUNT TYPE**

For details of the recommended soldering conditions, see the information document. "Device Mounting Manual for Surface Mounting (IEI-1207)."

Soldering Method	Soldering Conditions	Symbol for Recommended Conditions IR30-00	
Infrared Reflow	Package peak temp.: 230 °C Soldering time: within 30 sec (above 210 °C) Soldering times: 1, Days limitation: none*		
Vapor Phase Soldering	Package peak temp.: 215 °C Soldering time: within 40 sec (above 200 °C) Soldering times: 1, Days limitation: none*	VP15-00	
Wave Soldering	Soldering bath temp.: below 260 °C Soldering time: within 10 sec Soldering times: 1, Days limitation: none*	WS60-00	

 $<sup>\</sup>star$ : Stored days under storage conditions at 25 °C and below 65 % R.H. after the dry-pack has been opened.

## REFERENCE

Document Name	Document No.
NEC semiconductor device reliability/quality control system.	TEI-1202
Quality grade on NEC semiconductor devices.	IEI-1209
Semiconductor device mounting technology manual.	IEI-1207
Semiconductor device package manual.	IEI-1213
Guide to quality assurance for semiconductor devices.	MEI-1202
Semiconductor selection guide.	MF-1134

Note 1 Combination of soldering methods should be avoided.

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Application examples recommended by NEC Corporation

Standard: Computer, Office equipment, Communication equipment, Test and Measurement equipment, Machine tools, Industrial robots, Audio and Visual equipment, Other consumer products, etc.

Special: Automotive and Transportation equipment, Traffic control systems, Antidisaster systems, Anticrime systems, etc.

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